



Apparatus For High-Speed Surface Relief Measurement

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The Invention

An apparatus for measurement of surface relief provides a phase sensitive camera and processing to reconstruct a wavefront profile matching the surface when illuminated with a known light source thereby providing noncontact surface relief measurements

Additional Information

For More Information About the Inventors

- [Zongfu Yu](#)

Tech Fields

- [Analytical Instrumentation, Methods & Materials : Optics](#)
- [Analytical Instrumentation, Methods & Materials : Sensors](#)

For current licensing status, please contact Michael Carey at mcarey@warf.org or 608-960-9867